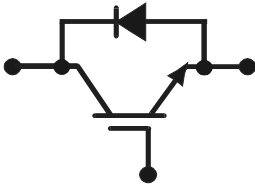


$V_{CE} = 3300\text{ V}$   
 $I_C = 1200\text{ A}$

**ABB HiPak™**



**IGBT Module**  
**5SNA 1200E330100**  
**PRELIMINARY**

Doc. No. 5SYA 1556-01 Oct 03

- Low-loss, rugged SPT chip-set
- Smooth switching SPT chip-set for good EMC
- Industry standard package
- High power density
- AlSiC base-plate for high power cycling capability
- AlN substrate for low thermal resistance



**Maximum rated values <sup>1)</sup>**

Parameter	Symbol	Conditions	min	max	Unit
Collector-emitter voltage	$V_{CES}$	$V_{GE} = 0\text{ V}$		3300	V
DC collector current	$I_C$	$T_c = 80\text{ °C}$		1200	A
Peak collector current	$I_{CM}$	$t_p = 1\text{ ms}, T_c = 80\text{ °C}$		2400	A
Gate-emitter voltage	$V_{GES}$		-20	20	V
Total power dissipation	$P_{tot}$	$T_c = 25\text{ °C}$ , per switch (IGBT)		14700	W
DC forward current	$I_F$			1200	A
Peak forward current	$I_{FM}$			2400	A
Surge current	$I_{FSM}$	$V_R = 0\text{ V}, T_{vj} = 125\text{ °C}$ , $t_p = 10\text{ ms}$ , half-sinewave		11000	A
IGBT short circuit SOA	$t_{psc}$	$V_{CC} = 2500\text{ V}, V_{CEMCHIP} \leq 3300\text{ V}$ $V_{GE} \leq 15\text{ V}, T_{vj} \leq 125\text{ °C}$		10	$\mu\text{s}$
Isolation voltage	$V_{isol}$	1 min, $f = 50\text{ Hz}$		6000	V
Junction temperature	$T_{vj}$			150	$^{\circ}\text{C}$
Junction operating temperature	$T_{vj(op)}$		-40	125	$^{\circ}\text{C}$
Storage temperature	$T_{stg}$		-40	125	$^{\circ}\text{C}$
Mounting torques	$M_1$	Base-heatsink, M6 screws	4	6	Nm
	$M_2$	Main terminals, M8 screws	8	10	

1) Maximum rated values indicate limits beyond which damage to the device may occur

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## IGBT characteristic values

Parameter	Symbol	Conditions	min	typ	max	Unit
Collector (-emitter) breakdown voltage	$V_{(BR)CES}$	$V_{GE} = 0 \text{ V}$ , $I_C = 10 \text{ mA}$ , $T_{vj} = 25 \text{ }^\circ\text{C}$	3300			V
Collector-emitter <sup>2)</sup> saturation voltage	$V_{CE \text{ sat}}$	$I_C = 1200 \text{ A}$ , $V_{GE} = 15 \text{ V}$		3.1		V
		$T_{vj} = 25 \text{ }^\circ\text{C}$				V
		$T_{vj} = 125 \text{ }^\circ\text{C}$		3.8		V
Collector cut-off current	$I_{CES}$	$V_{CE} = 3300 \text{ V}$ , $V_{GE} = 0 \text{ V}$			12	mA
		$T_{vj} = 25 \text{ }^\circ\text{C}$			120	mA
		$T_{vj} = 125 \text{ }^\circ\text{C}$				mA
Gate leakage current	$I_{GES}$	$V_{CE} = 0 \text{ V}$ , $V_{GE} = \pm 20 \text{ V}$ , $T_{vj} = 125 \text{ }^\circ\text{C}$	-500		500	nA
Gate-emitter threshold voltage	$V_{GE(TO)}$	$I_C = 240 \text{ mA}$ , $V_{CE} = V_{GE}$ , $T_{vj} = 25 \text{ }^\circ\text{C}$	6		8	V
Gate charge	$Q_{ge}$	$I_C = 1200 \text{ A}$ , $V_{CE} = 1800 \text{ V}$ , $V_{GE} = -15 \text{ V} \dots 15 \text{ V}$		12.1		$\mu\text{C}$
Input capacitance	$C_{ies}$	$V_{CE} = 25 \text{ V}$ , $V_{GE} = 0 \text{ V}$ , $f = 1 \text{ MHz}$ , $T_{vj} = 25 \text{ }^\circ\text{C}$		187		nF
Output capacitance	$C_{oes}$			11.57		
Reverse transfer capacitance	$C_{res}$			2.22		
Turn-on delay time	$t_{d(on)}$	$V_{CC} = 1800 \text{ V}$ , $I_C = 1200 \text{ A}$ , $R_G = 1.5 \text{ }^\circ\Omega$ ,	$T_{vj} = 25 \text{ }^\circ\text{C}$	400		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	400		
Rise time	$t_r$	$V_{GE} = \pm 15 \text{ V}$ , $L_\sigma = 100 \text{ nH}$ , inductive load	$T_{vj} = 25 \text{ }^\circ\text{C}$	175		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	200		
Turn-off delay time	$t_{d(off)}$	$V_{CC} = 1800 \text{ V}$ , $I_C = 1200 \text{ A}$ , $R_G = 1.5 \text{ }^\circ\Omega$ ,	$T_{vj} = 25 \text{ }^\circ\text{C}$	940		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	1070		
Fall time	$t_f$	$V_{GE} = \pm 15 \text{ V}$ , $L_\sigma = 100 \text{ nH}$ , inductive load	$T_{vj} = 25 \text{ }^\circ\text{C}$	350		ns
			$T_{vj} = 125 \text{ }^\circ\text{C}$	440		
Turn-on switching energy	$E_{on}$	$V_{CC} = 1800 \text{ V}$ , $I_C = 1200 \text{ A}$ , $V_{GE} = \pm 15$ , $R_G = 1.5 \text{ }^\circ\Omega$ , $L_\sigma = 100 \text{ nH}$ , inductive load	$T_{vj} = 25 \text{ }^\circ\text{C}$	1340		mJ
			$T_{vj} = 125 \text{ }^\circ\text{C}$	1890		
Turn-off switching energy	$E_{off}$	$V_{CC} = 1800 \text{ V}$ , $I_C = 1200 \text{ A}$ , $V_{GE} = \pm 15$ , $R_G = 1.5 \text{ }^\circ\Omega$ , $L_\sigma = 100 \text{ nH}$ , inductive load	$T_{vj} = 25 \text{ }^\circ\text{C}$	1420		mJ
			$T_{vj} = 125 \text{ }^\circ\text{C}$	1950		
Short circuit current	$I_{SC}$	$t_{psc} \leq 10 \text{ }^\circ\mu\text{s}$ , $V_{GE} = 15 \text{ V}$ , $T_{vj} = 125 \text{ }^\circ\text{C}$ , $V_{CC} = 2500 \text{ V}$ , $V_{CEM \text{ CHIP}} \leq 3300 \text{ V}$		5000		A
Module stray inductance	$L_{\sigma \text{ CE}}$			10		nH
Resistance, terminal-chip	$R_{CC'+EE'}$		$T_C = 25 \text{ }^\circ\text{C}$	0.06		m $\Omega$
			$T_C = 125 \text{ }^\circ\text{C}$	0.085		

2) Collector emitter saturation voltage is given at chip level

**Diode characteristic values**

Parameter	Symbol	Conditions	min	typ	max	Unit
Continuous forward voltage <sup>3)</sup>	$V_F$	$I_F = 1200 \text{ A}$	$T_{vj} = 25 \text{ °C}$	2.3		V
			$T_{vj} = 125 \text{ °C}$		2.35	
Peak reverse recovery current	$I_{RM}$	$V_{CC} = 1800 \text{ V},$ $I_F = 1200 \text{ A},$ $V_{GE} = \pm 15 \text{ V},$ $R_G = 1.5 \text{ } \Omega$ $L_\sigma = 100 \text{ nH}$ inductive load	$T_{vj} = 25 \text{ °C}$	1100		A
			$T_{vj} = 125 \text{ °C}$		1350	
Recovered charge	$Q_{RR}$	$V_{CC} = 1800 \text{ V},$ $I_F = 1200 \text{ A},$ $V_{GE} = \pm 15 \text{ V},$ $R_G = 1.5 \text{ } \Omega$ $L_\sigma = 100 \text{ nH}$ inductive load	$T_{vj} = 25 \text{ °C}$	715		$\mu\text{C}$
			$T_{vj} = 125 \text{ °C}$		1280	
Reverse recovery time	$t_{rr}$	$V_{CC} = 1800 \text{ V},$ $I_F = 1200 \text{ A},$ $V_{GE} = \pm 15 \text{ V},$ $R_G = 1.5 \text{ } \Omega$ $L_\sigma = 100 \text{ nH}$ inductive load	$T_{vj} = 25 \text{ °C}$	520		ns
			$T_{vj} = 125 \text{ °C}$		1450	
Reverse recovery energy	$E_{rec}$	$V_{CC} = 1800 \text{ V},$ $I_F = 1200 \text{ A},$ $V_{GE} = \pm 15 \text{ V},$ $R_G = 1.5 \text{ } \Omega$ $L_\sigma = 100 \text{ nH}$ inductive load	$T_{vj} = 25 \text{ °C}$	840		mJ
			$T_{vj} = 125 \text{ °C}$		1530	

3) Forward voltage is given at chip level

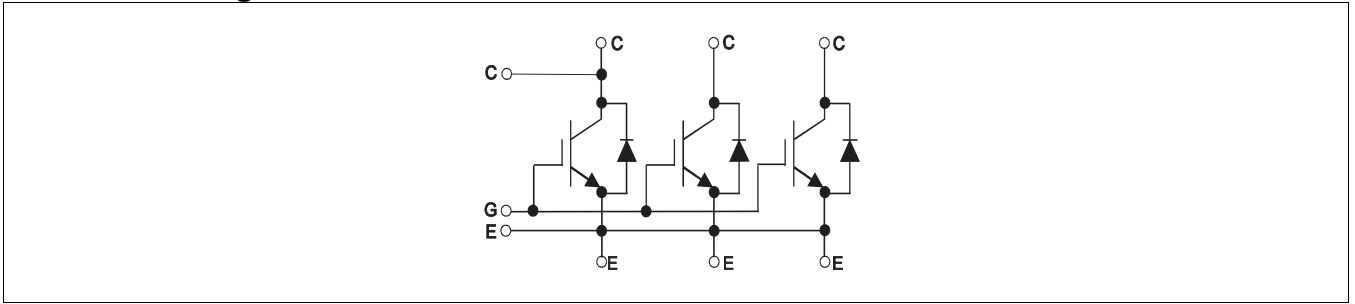
**Thermal properties**

Parameter	Symbol	Conditions	min	typ	max	Unit
IGBT thermal resistance junction to case	$R_{th(j-c)IGBT}$				0.0085	K/W
Diode thermal resistance junction to case	$R_{th(j-c)DIODE}$				0.017	K/W
Thermal resistance case to heatsink	$R_{th(c-h)}$	per module, $\lambda$ grease = $1\text{W/m} \times \text{K}$		0.006		K/W

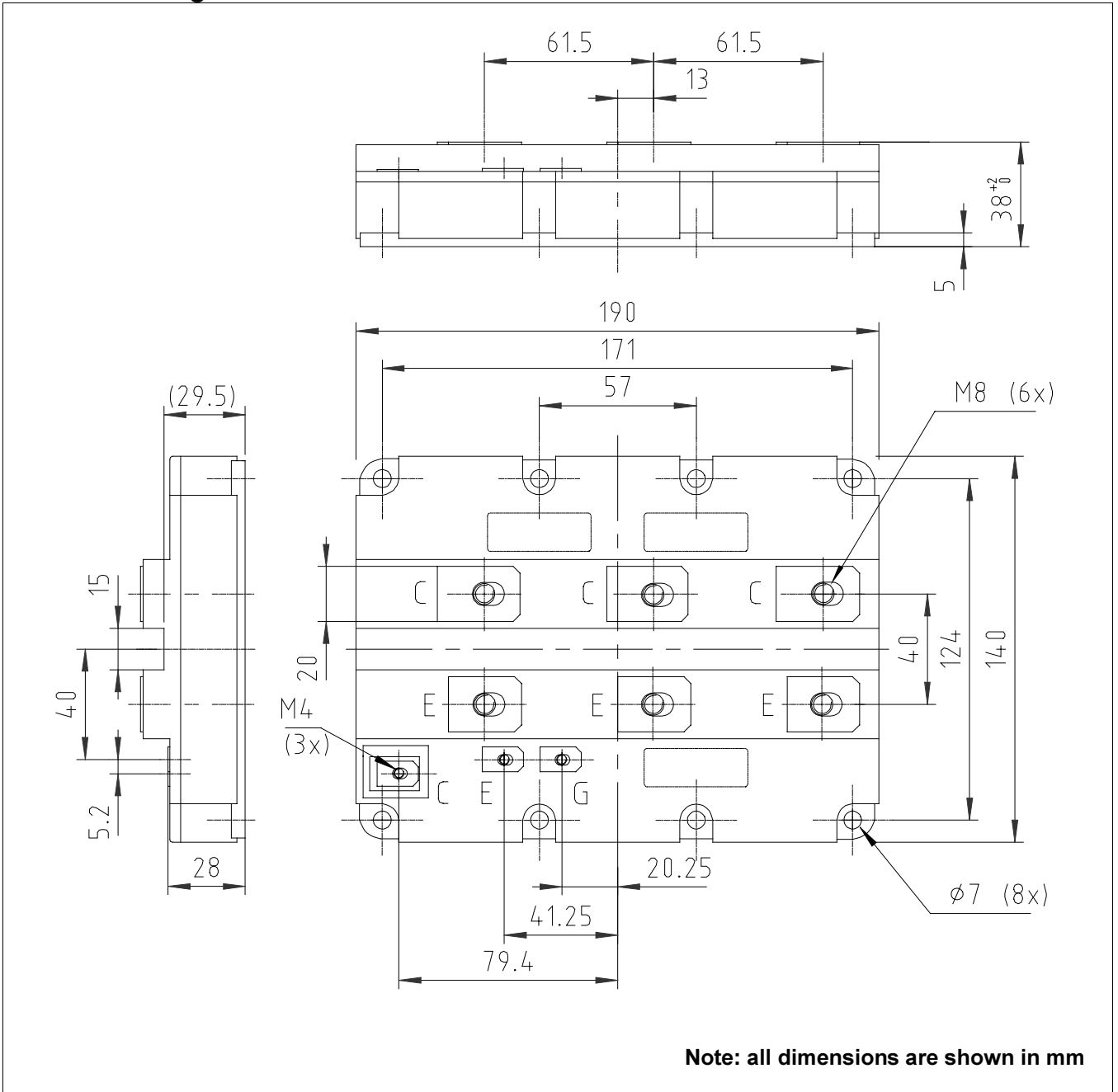
**Mechanical properties**

Parameter	Symbol	Conditions	min	typ	max	Unit
Dimensions	$L \times W \times H$	Typical , see outline drawing	190 × 140 × 38			mm
Clearance distance	$D_C$	according to IEC 60664-1 and EN 50124-1	Term. to base:	23		mm
			Term. to term:	19		
Surface creepage distance	$D_{SC}$	according to IEC 60664-1 and EN 50124-1	Term. to base:	33		mm
			Term. to term:	32		
Weight				1500		gr

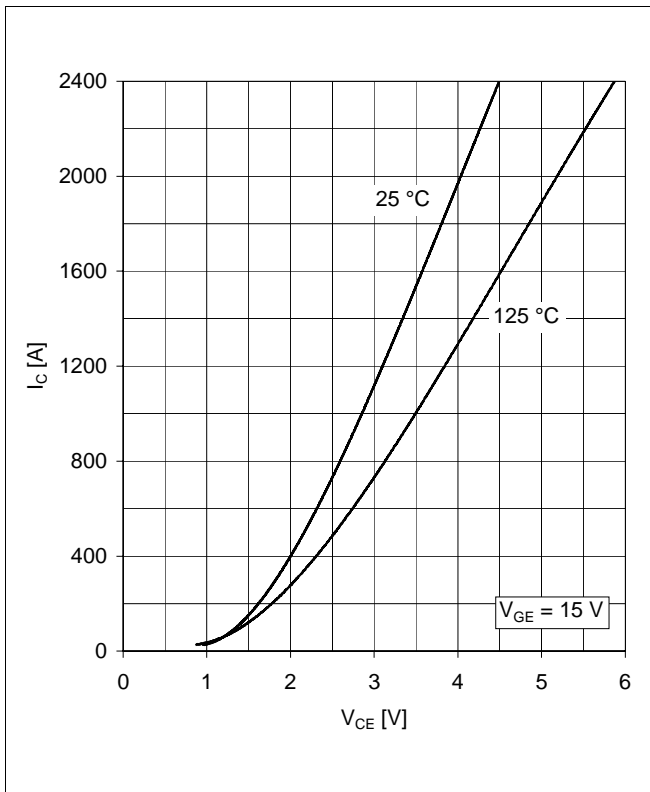
**Electrical configuration**



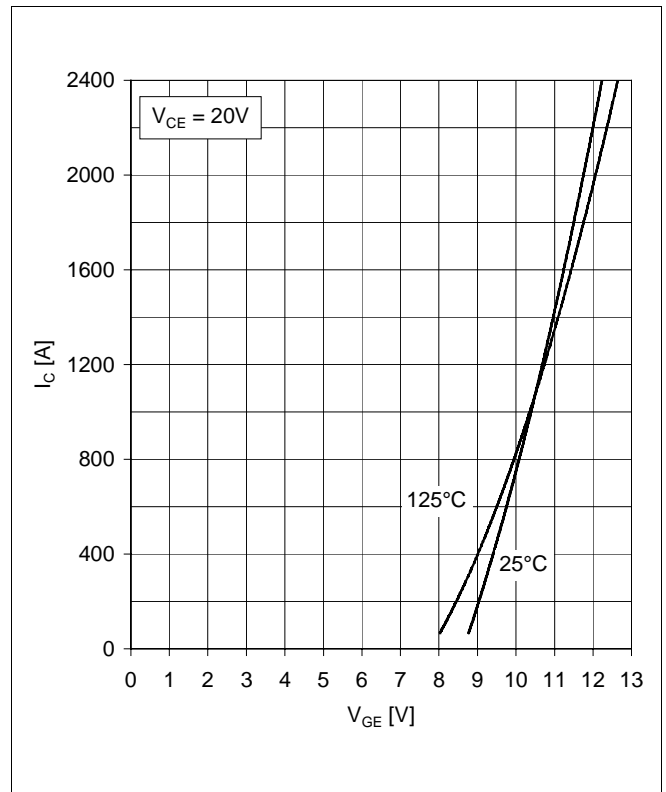
**Outline drawing**



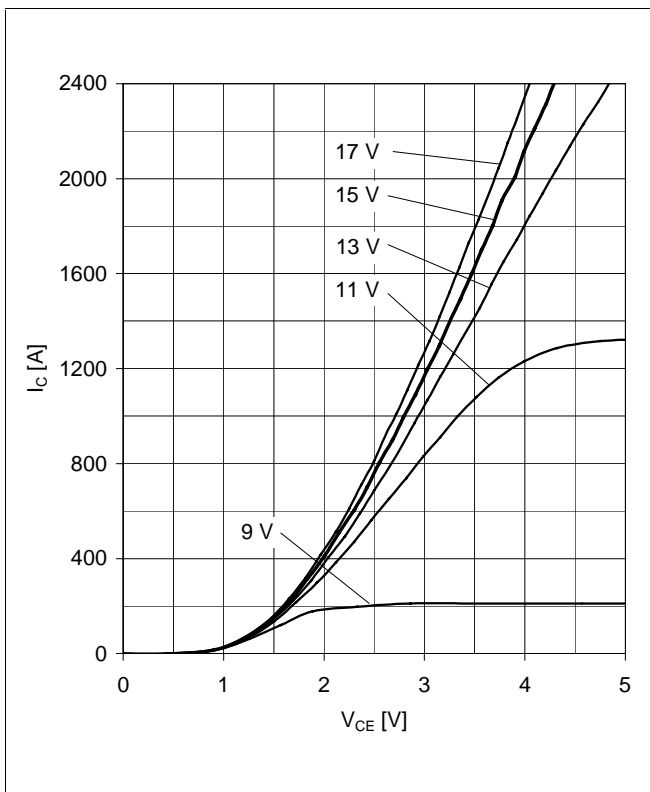
**This is an electrostatic sensitive device, please observe the international standard IEC 60747-1, chap. IX.**



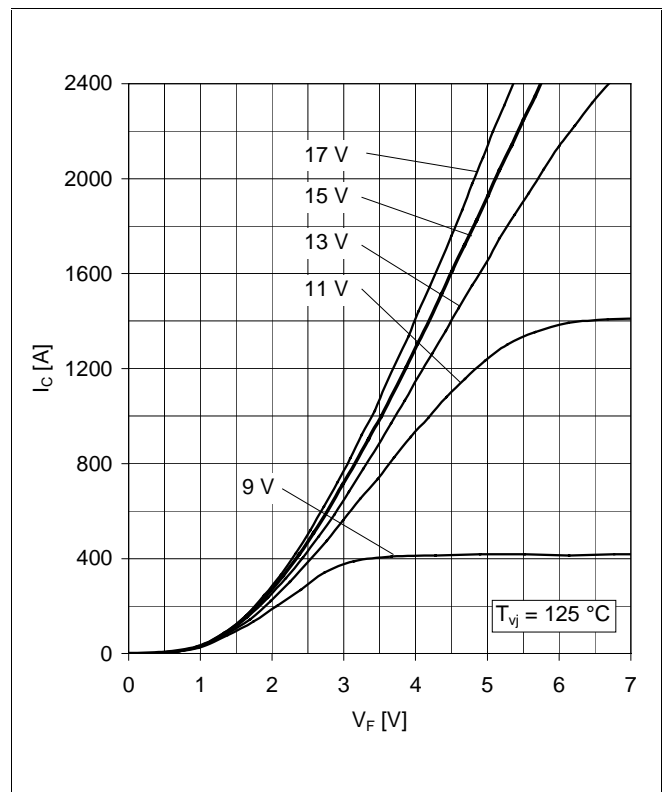
**Fig. 1** Typical onstate characteristics, chip level



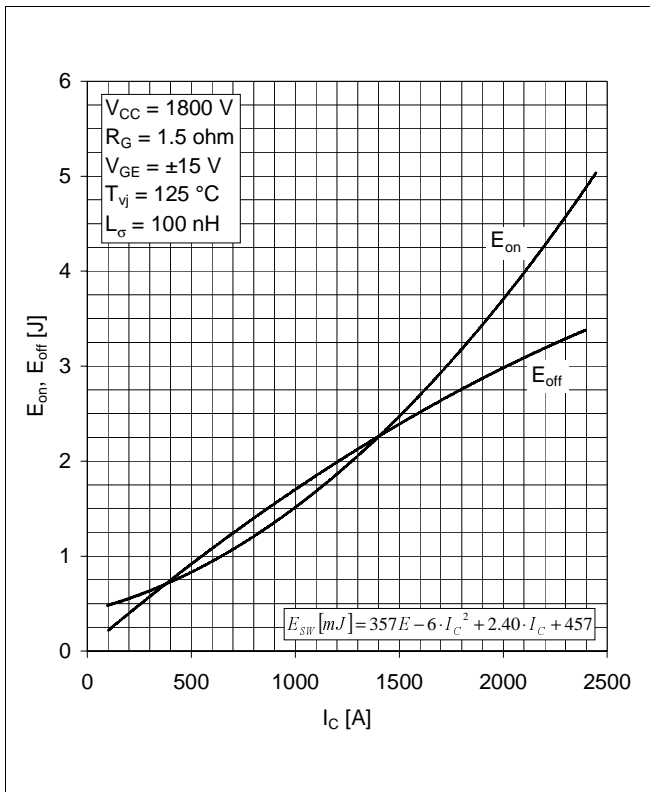
**Fig. 2** Typical transfer characteristics, chip level



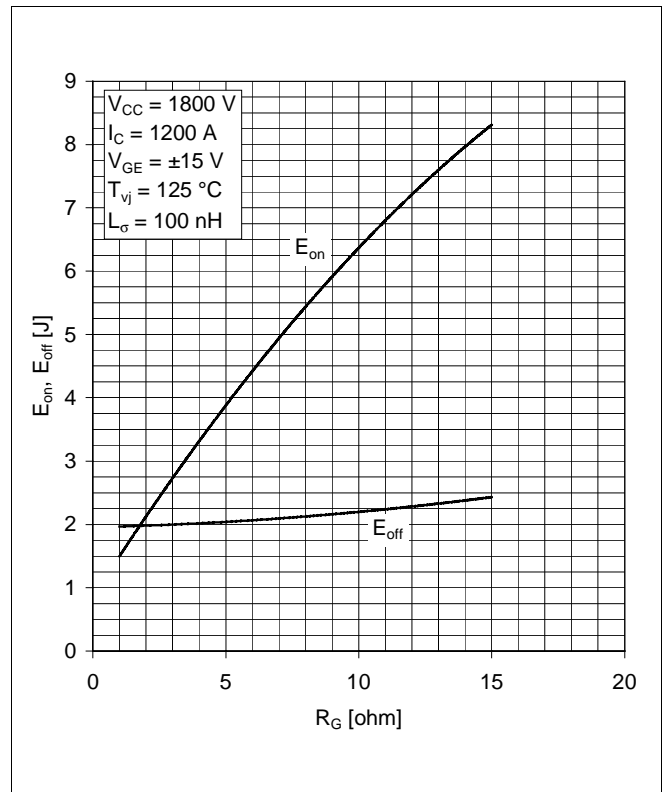
**Fig. 3** Typical output characteristics, chip level



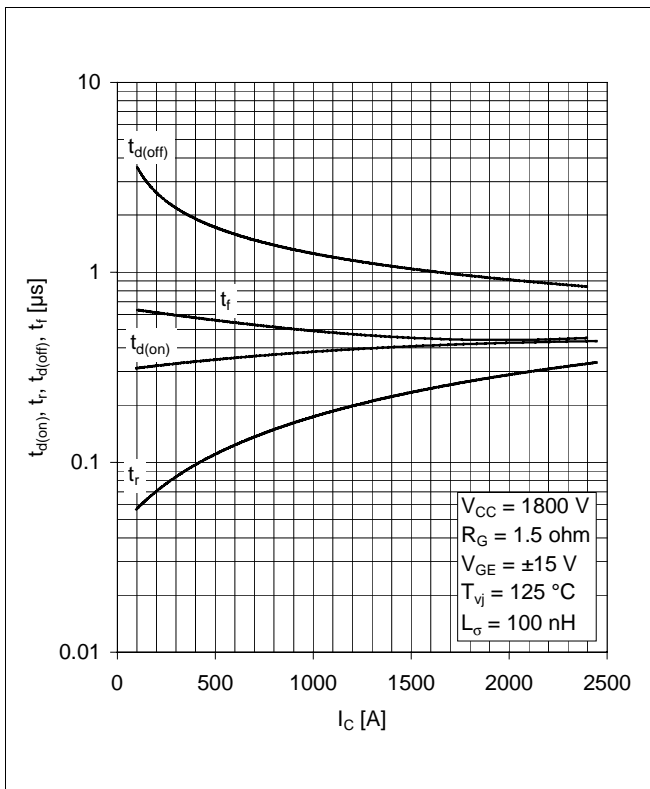
**Fig. 4** Typical output characteristics, chip level



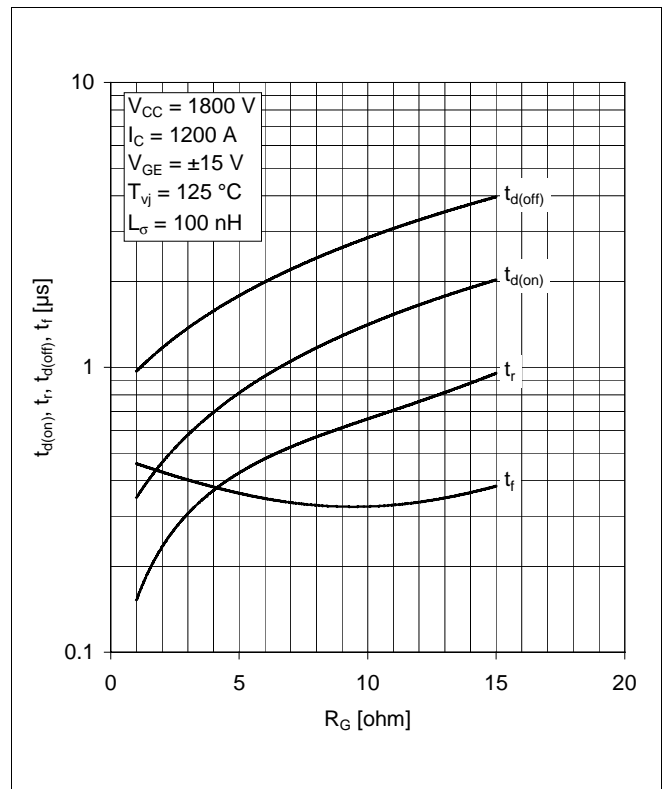
**Fig. 5** Typical switching energies per pulse vs collector current



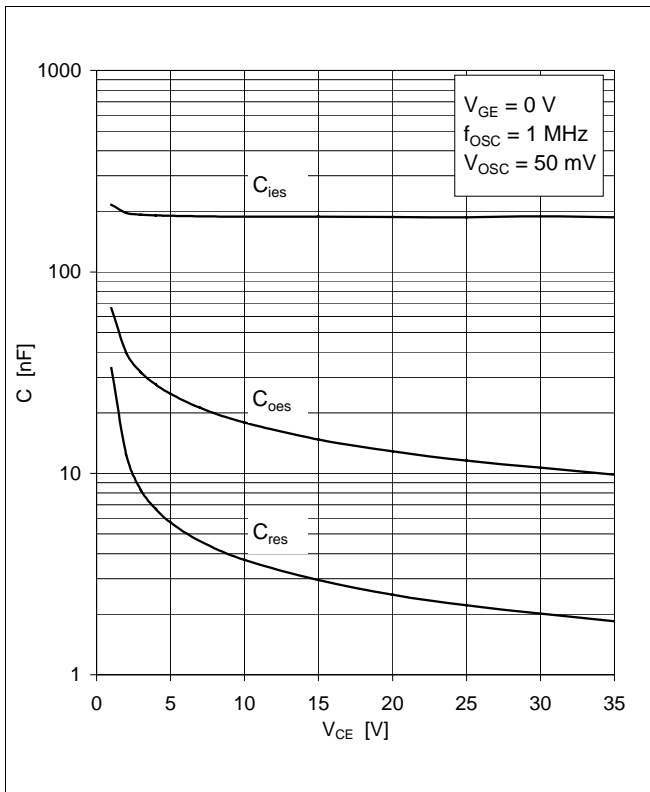
**Fig. 6** Typical switching energies per pulse vs gate resistor



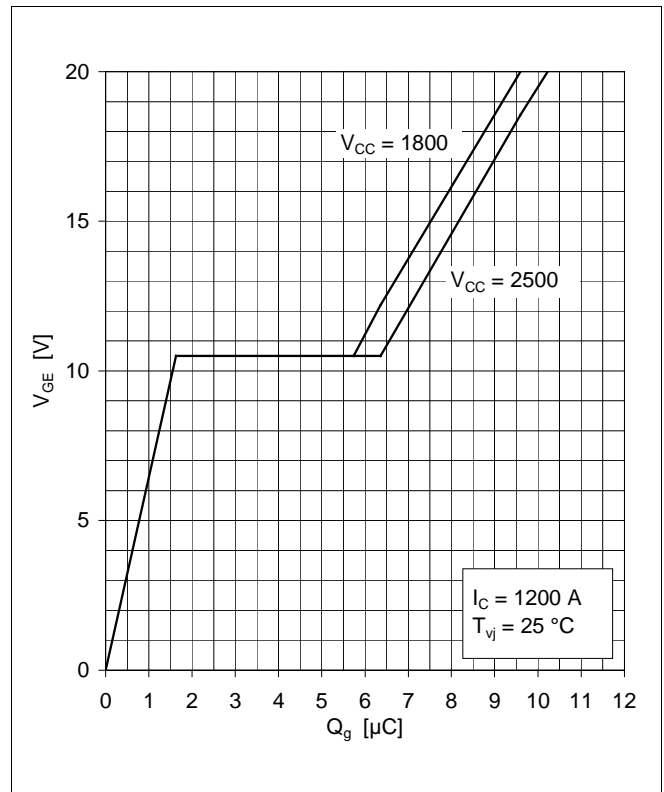
**Fig. 7** Typical switching times vs collector current



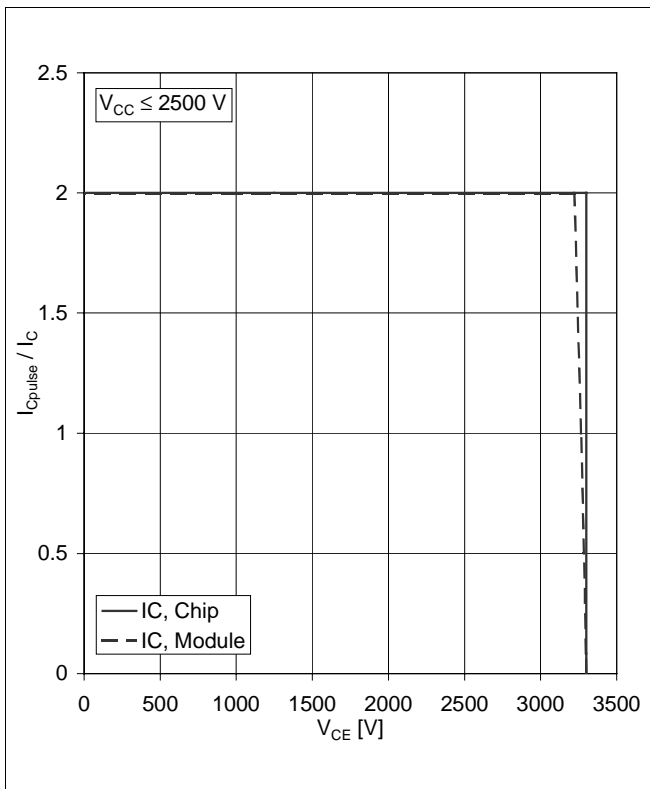
**Fig. 8** Typical switching times vs gate resistor



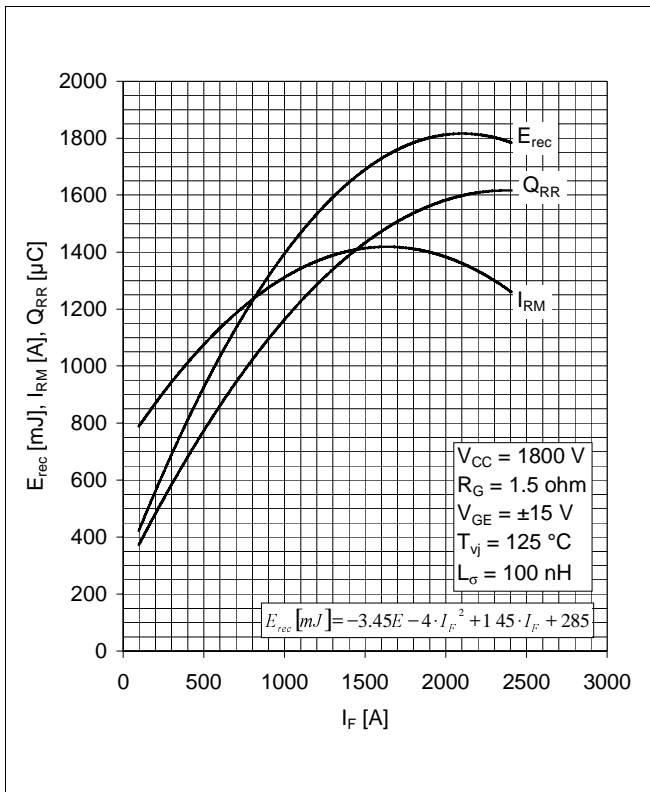
**Fig. 9** Typical capacitances vs collector-emitter voltage



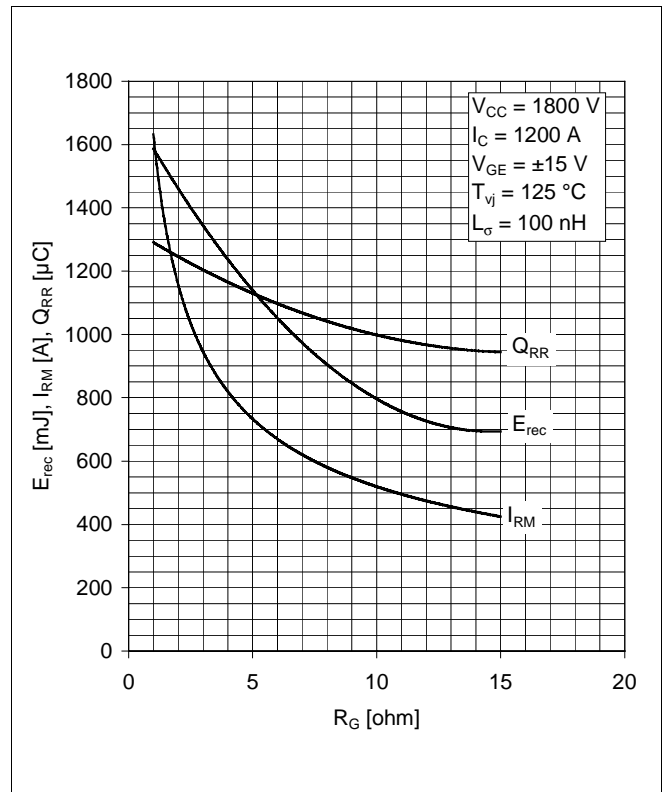
**Fig. 10** Typical gate charge characteristics



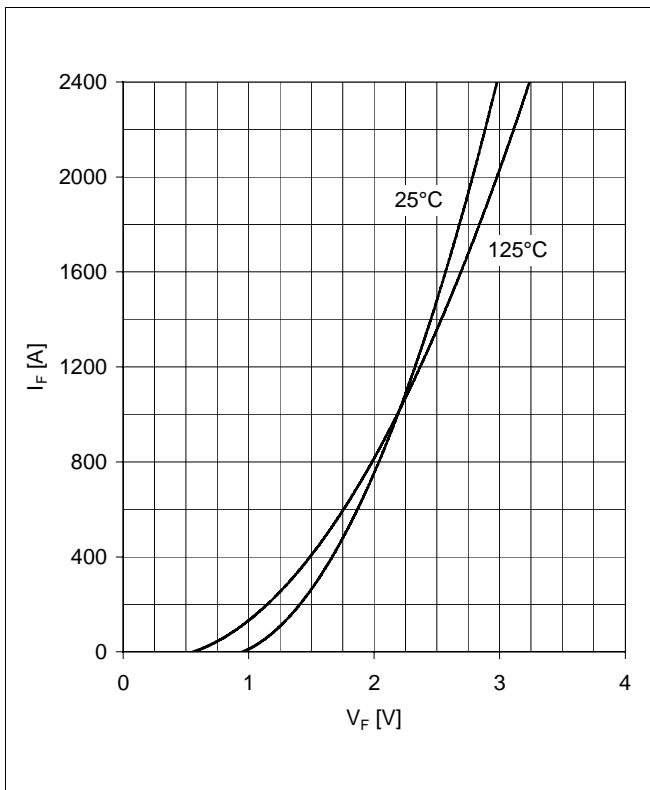
**Fig. 11** Turn-off safe operating area (RBSOA)



**Fig. 12** Typical reverse recovery characteristics vs forward current



**Fig. 13** Typical reverse recovery characteristics vs gate resistor



**Fig. 14** Typical diode forward characteristics, chip level



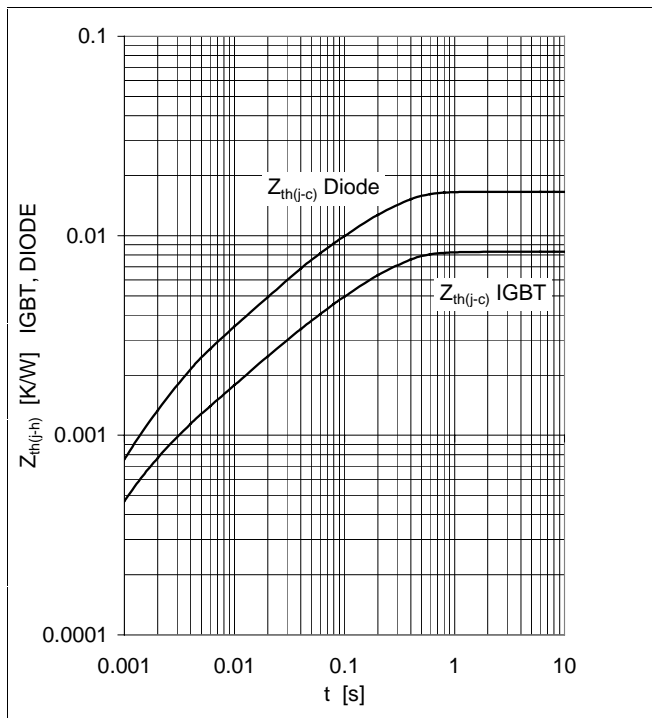


Fig. 15 Thermal impedance vs time

Analytical function for transient thermal impedance:

$$Z_{th\,JC}(t) = \sum_{i=1}^n R_i(1 - e^{-t/\tau_i})$$

	i	1	2	3	4	5
IGBT	R <sub>i</sub> (K/kW)	5.50	1.53	0.621	0.646	
	τ <sub>i</sub> (ms)	193	31.2	8.0	1.48	
DIODE	R <sub>i</sub> (K/kW)	11.2	3.73	1.30	0.42	
	τ <sub>i</sub> (ms)	189	24.5	2.69	2.36	

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